IEC 63004

Edition 1.0 2015-12

INTERNATIONAL STANDARD

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Standard for receiver fixture interface



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IEEE Std 1505-2010	91/1275/FDIS	91/1299/RVD

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IEEE Std 1505™-2010
(Revision of
IEEE Std 1505-2006)

IEEE Standard for Receiver Fixture Interface

Sponsor

IEEE Standards Coordinating Committee 20 on Test and Diagnosis for Electronic Systems

Approved 30 September 2010

IEEE-SA Standards Board

Approved 15 July 2011

American National Standards Institute

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Abstract: A mechanical and electrical specification for implementing a common interoperable mechanical quick-disconnect interconnect system for use by industry for interfacing large numbers of electrical signals (digital, analog, RF, power, etc.) is provided. These large interface panels (receiver and fixture panels) are employed primarily in test systems between stimulus/measurement assets and a related unit-under-test (UUT), although any application involving high-density contacts requiring a quick disconnect interface could benefit. The *receiver* is a receptacle that is mounted to test system mates with multiple *fixtures*, which serve as the *buffer* between the UUT and automatic test equipment (ATE). Fixtures translate standard input/output (I/O) signal routing offered at the receiver to a wiring interface that directly connects to the UUT. These UUT interfaces can represent cable connectors, direct plug-in (printed circuit board edge connectors), sensor monitoring, or manual feedback from the test technician.

The primary objectives of this standard are: (a) to establish interface standards that permit interchangeability of mechanical/electrical receiver/fixture/connector product assemblies from various manufacturers under an *open architecture*; and (b) to develop within this framework a defined set(s) of interconnecting connector and mechanical specifications that supports available, accepted, low-cost commercial technology to reduced dependence on proprietary designs and extend life-cycle availability.

Keywords: connector, fixture, framework, interface, interoperability, mass-interconnect, quick disconnect, receiver, specification

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IEEE Introduction

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Historical Background

On September 19, 1996, a group of receiver fixture product vendors/integrators announced the formation of an industry standards group called the RFI Alliance.

The organization later sought to gain identity through a standards organization, which ultimately became the Institute of Electrical and Electronic Engineers, Inc. (IEEE). Under the joint sponsorship of the Instrumentation and Measurement Society TC-5 Connectors/TC-8 Automated Instruments Committees and SCC20 Hardware Interface Subcommittee, an IEEE Std 1505 RFI Working Group was developed and authorized by the IEEE Standards Association. Participation in the IEEE Std 1505 RFI Working Group is open to vendors, integrators, and users.

IEEE Std 1505 Receiver Fixture Interface (RFI) Working Group focus

The IEEE Std 1505 RFI Working Group, sponsored by the IEEE Instrumentation and Measurement Society and IEEE SCC20, Test and Diagnosis for Electronic Systems, was formed to define a common electrical/mechanical interface specifications for applications involving test, production processing, quick-disconnect electrical interfacing, and subassembly mating requirements. The group is made up of technical individuals from industry, government, and academia, which reflect perspective views of a supplier, user, and general interest in the standard. To derive these specifications, the IEEE Std 1505 Working Group utilized the results of a study conducted by the Department of Defense Automatic Test System Research & Development Integrated Product Team (ARI) Critical Interface Working Group (CIWG), which reviewed as part of their tasks the Automatic Test System (ATS) Test Interface and the joint industry/government Common Test Interface (CTI) Working Group. The methodology step process includes: (a) defining the problem, (b) establishing a set of requirements, (c) evaluating available interface designs against a set of parameters that relate to the problem and requirements, and (d) defining a specification that will meet the consensus of the Working Group and industry short- and long-term goals. It was designed upon open standards or functional specifications that are supported by multiple-vendor products.

Cooperative relationship with the Common Test Interface

This document serves as the basis for supplemental pin map configuration standards, such as IEEE Std 1505.1-2008 and others that are expected to meet unique pin map requirements. Future revisions to this document may add new connector styles or types that support RFI needs.

The IEEE Std 1505 Working Group recognizes industry/government end-user integration and maintenance support of a defined CTI, a specific connector/pin map implementation of the standard. This document provides for these CTI end-users, and for its ATE system and hardware integrators, a defined, standardized framework and connector, and configuration specification to enable agency/aerospace interoperability and upward compatibility. The CTI Working Group has developed a *common test interface pin map configuration* (IEEE Std 1505.1) that uses this standard as its basis.

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Standard for Receiver Fixture Interface

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1. Overview

1.1 Scope

The scope of this standard is the development of a common receiver fixture interface (RFI) specification that is based upon available commercial standards integrated under a common *open architecture*. This mechanical/electrical interface is intended to serve government/commercial interest for applications in test, system integration, manufacturing, monitoring, and other functional requirements that demand large contact densities and quick-disconnect mechanical operation.

1.2 Purpose

The purpose of this standard is to permit interchangeability of mechanical/electrical receiver/fixture/connector product assemblies from various manufacturers under an open architecture. The standard shall also define, within this framework, a set(s) of interconnecting connector and mechanical specifications that support available, accepted, low-cost commercial technology to reduce dependence on proprietary designs and extend life-cycle availability. Technical requirements incorporated shall be those identified by government and industry, including maximum flexibility, scalability, and range of application.

1.3 Background

A joint technical forum has been operational since 1997 under the auspices of the IEEE Std 1505 RFI Working Group.

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The RFI Working Group serves to encourage vendors to produce same product class types that are intermatable and interchangeable by adhering to performance specifications of this standard.

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1.4 Annexes overview

Included within this document are three informative annexes: Annex A, an overview of the RFI description, background, and application use to inform new users; Annex B, the results of a study conducted by the Department of Defense Automatic Test System Research and Development Integrated Product Team (ARI) Critical Interface Working Group (CIWG), which reviewed as part of their tasks the automatic test system (ATS) test interface[2];and Annex C, an informative bibliography.

2. Normative references

The following referenced documents are indispensable for the application of this document (i.e., they must be understood and used, so each referenced document is cited in text and its relationship to this document is explained). For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments or corrigenda) applies.

ASTM A240, Standard Specification for Chromium and Chromium-Nickel Stainless Steel Plate, Sheet, and Strip for Pressure Vessels and for General Applications; equivalent to SAE-AMS-QQ-S-766.[3]

ASTM A342, Standard Test Methods for Permeability of Feebly Magnetic Materials; equivalent to MIL-I-17214.

ASTM A484M-03, Standard Specification for General Requirements for Stainless Steel Bars, Billets, and Forgings.

ASTM A581, Standard Specification for Free-Machining Stainless Steel Wire and Wire Rods.

ASTM A582M-05, Standard Specification for Free-Machining Stainless Steel Bars.

ASTM A666-00, Standard Specification for Annealed or Cold-Worked Austenitic Stainless Steel Sheet, Strip, Plate, and Flat Bar.

ASTM A693-06, Standard Specification for Precipitation-Hardening Stainless and Heat-Resisting Steel Plate, Sheet, and Strip.

[1] The numbers in brackets correspond to those of the bibliography in Annex C.
[2] For more information, see http://grouper.ieee.org/groups/scc20/HIWG/index.htm.
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ASTM A967-1999E1, Standard Specification for Chemical Passivation Treatments for Stainless Steel Parts; supersedes SAE AMS QQ-P-35C Passivation Treatments for Corrosion-Resistant Steel (cancelled February 2005).

ASTM B16, Standard Specification for Free-Cutting Brass Rod, Bar and Shapes for Use in Screw Machines.

ASTM B36/B36M-08a, Standard Specification for Brass Plate, Sheet, Strip, and Rolled Bar.

ASTM B103, Standard Specification for Phosphor Bronze Plate, Sheet, Strip, and Rolled Bar.

ASTM B121/B121M, Standard Specification for Leaded Brass Plate, Sheet, Strip, and Rolled Bar; and related Federal Specification QQ-B-626 D, Brass, Leaded and Nonleaded: Rod, Shapes, Forgings, and Flat Products with Finished Edges (Bar and Strip).

ASTM B134, Standard Specification for Brass Wire.

ASTM B139/B139M-07, Standard Specification for Phosphor Bronze Rod, Bar, and Shapes; and related Federal Specification QQ-B-750, Phosphor Bronze Bar, Flat Wire, Plate, Sheet, Strip, and Structural Shapes.

ASTM B159, Standard Specification for Wire Phosphor Bronze.

ASTM B194, Standard Specification for Copper-Beryllium Alloy Plate, Sheet, Strip, and Rolled Bar; and related Federal Specification for QQ-C-530/533 Beryllium-Copper (BeCu) Bar, Rod, and Wire/Strip.

ASTM B196, Standard Specification for Copper-Beryllium Alloy Rod and Bar.

ASTM B197, Standard Specification for Copper-Beryllium Alloy Wire.

ASTM B206/B206M, Copper-Nickel-Zinc (Nickel Silver) Wire and Copper-Nickel Alloy Wire; and related Federal Specification QQ-W-321, Copper alloy wire).

ASTM B209-07, Standard Specification for Aluminum and Aluminum-Alloy Sheet and Plate (related to SAE AMS-QQ-A-250/1A, -250/2A, -250/4A, -250/8B, 250/11A, and -250/13 for Aluminum Alloy 3003/ 2024/5052/6061/and 7075, Plate and Sheet).

ASTM B301/B301M-08, Standard Specification for Free Cutting Copper Rod, Bar, Wire and Shapes.

ASTM B441-04, Standard Specification for Copper-Cobalt-Beryllium, Copper-Nickel-Beryllium, and Copper-Nickel-Lead-Beryllium Rod and Bar (UNS Nos. C17500, C17510, and C17465).

ASTM B488-01(2006), Standard Specification for Electrodeposited Coatings of Gold for Engineering Uses (equivalent to SAE AMS-2422 and MIL-G-45204).

ASTM B740-02, Standard Specification for Copper-Nickel-Tin Spinodal Alloy Strip.

ASTM D4067-03, Standard Specification for Reinforced and Filled Poly(Phenylene Sulfide) (PPS) Injection Molding and Extrusion Materials Using ASMT Methods.

ASTM D5927-09, Standard Specification for Thermoplastic Polyester (TPES) Injection and Extrusion Materials Based on ISO Test, Methods.

ASTM D5948-05e1, Standard Specification for Molding Compounds, Thermosetting.

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EIA 364E, Electrical Connector/Socket Test Procedures including Environmental Classifications.[4]

EIA 557B, General Standard for Statistical Process Control Systems.

FED-STD-H28, Screw Thread Standards for Federal Services.[5]

IEC 60309-1, Plugs, socket-outlets, and couplers for industrial purposes—Part 1: General Requirements.[6]

IPC-D-275, Design Standard for Rigid Printed Boards and Rigid Printed Board Assemblies.[7]

ISO 10012-1, Quality Assurance Requirements for Measuring Equipment—Part 1: Meteorological Confirmation System for Measuring Equipment.[8]

ISO/IEC 17025:2005/ANSI/NCSL Z540-1, General Requirements for the Competence of Testing and Calibration Laboratories.[9]

MIL-C-24308C, General Specification for Connectors, Electric, Rectangular, Nonenvironmental, Miniature, Polarized Shell, Rack, and Panel. [10]

MIL-C-83517, General Specification for Connector, Coaxial, Radio Frequency for Coaxial, Strip or Microstrip Transmission Line.

MIL-DTL-14072, Finishes for Ground Based Electronic Equipment.

MIL-DTL-16878, General Requirements for Wire, Electrical, Insulated.

MIL-DTL-55302, Connectors, Printed Circuit Subassembly and Accessories,

MIL-HDBK-217F, Reliability Prediction of Electronic Equipment.

MIL-HDBK-454B/4, General Guidelines for Electronic Equipment.

MIL-M-24519E, Military Specification for Molding Plastics, Polyester Thermoplastic, Polyarylether Thermoplastic, Plastic Molding Material, Polyphenylene Sulfide, Glass Fiber Reinforced.

MIL-M-24519/GPT-30F, Thermoplastic polyetherimide compound, 30 percent glass reinforced, flame resistant.

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[4] EIA publications are available from Global Engineering Documents, 15 Inverness Way East, Englewood, Colorado 80112, USA (http://global.ihs.com/).

[5] Fed-Std publications are available from the Defense Industrial Supply Center, 700 Robbins Avenue, Bldg 3 (Code DISSC-ETT), Philadelphia, PA 19111-5096 (www.wbdg.org/ccb/FEDMIL/fedstdh28a.pdf).

[6] IEC publications are available from the Sales Department of the International Electrotechnical Commission, Case Postale 131, 3, rue de Varembé, CH-121 1, Genève 20, Switzerland/Suisse (http://www.iec.ch/). IEC publications are also available in the United States from the Sales Department, American National Standards Institute, 25 West 43rd Street, 4th Floor, New York, NY 10036, USA (http:// www.ansi.org/).

[7] IPC publications are available from the Association Connecting Electronics Industries, 3000 Lakeside Drive, 309 S, Bannockburn, IL 60015 or at IPC-D-275 Design Standard for Rigid Printed Boards and Rigid Printed Board Assemblies, IPC-RB-276 Qualification and Performance Specification (www.ipc.org/TOC/IPC-MIL-960.pdf).

[8] ISO publications are available from the ISO Central Secretariat, Case Postale 56, 1 rue de Varembé, CH-121 1, Genève 20, Switzerland/ Suisse (http://www.iso.ch/). ISO publications are also available in the United States from the Sales Department, American National Standards Institute, 25 West 43rd Street, 4th Floor, New York, NY 10036, USA (http://www.ansi.org/).

[9] ISO/IEC publications are also available in the United States from the Sales Department, American National Standards Institute, 25 West 43rd Street, 4th Floor, New York, NY 10036, USA (http://www.ansi.org/). See also www.ecalibration.com/ Resources/17025b.htm.

[10] Copies of specifications, standards, drawings, and publications required by manufacturers in connection with specific procurement functions may be obtained from the U.S. Government Printing Office, P.O. Box 37082, Washington, DC 20013-7082, USA (http://www.access.gpo.gov/) or from other sources that may require additional fees. See also http://store.mil-standards.com/.

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MIL-M-24519/GST-40F, Thermoplastic polyphenylene sulfide compound, 40 percent glass reinforced, flame resistant.

MIL-PRF-31032, General Specification for Printed Circuit Board/Printed Wiring Board (with Amendment 1) Revision: A, Dated: 24 February 2006.

MIL-PRF-55110, General Specification for Printed Wiring Board, Rigid, (with Amendment 1) FSC 5998.

MIL-STD-1130, Connections, Electrical, Solderless Wrapped (standard has been cancelled with no replacement and should be used for guidance only).

MIL-STD-1285D, Marking of Electrical and Electronic Parts.

MIL-STD-1344A, Test Methods for Electrical Connectors (equivalent standard EIA 364).

MIL-STD-202G, Test Method Standard for Electronic Components.

MIL-STD-2166, Connections, Electrical, Compliant Pin.

MIL-STD-275, Printed Wiring for Electronic Equipment (superseded by IPC-D-275).

MIL-STD-810F, Test Method Standard for Environmental Engineering Considerations and Laboratory Tests.

MIL-STD-889B, Dissimilar Metals.

MS3197, Gage Pin for Socket Contact Engagement Test (superseded by SAE AMS-31971).[11]

OSHA CPL 02-01-038 [CPL 2-1.38] (October 31, 2002), Enforcement of the Electrical Power Generation, Transmission, and Distribution Standard.[12]

OSHA STD 01-16-007 [STD 1-16.7], Electrical Safety-Related Work Practices—Inspection Procedures and Interpretation Guidelines.[13]

OSHA Technical Manual (OTM), TED 01-00-015 [TED 1-0.15A] (January 20, 1999).

SAE AMS-QQ-N-290, Nickel Plating (Electrodeposited).[14]

SAE AMS-QQ-S-763, Steel, Corrosion-Resistant, Bars, Wire, Shapes, and Forgings.

SAE AMS-3197, Gauge Pin for Socket Contact Engagement Test (equivalent to MS-3197).

SAE AMS-P-81728, Plating, Tin-Lead (Electrodeposited) (equivalent to MIL-P-81728).

SAE AMS-2422, Gold Plating for Electronic and Electrical Application (equivalent to ASTM B488 and MIL-G-45204).

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[11] This document is available from Global Engineering Documents, 15 Inverness Way East, Englewood, Colorado 80112, USA (http://global.ihs.com/).
[12] U.S. Regulatory Guides are available from the Superintendent of Documents, U.S. Government Printing Office, P.O. Box 37082, Washington, DC 20013-7082, USA (http://www.access.gpo.gov/).
[13] Occupational Safety & Health Administration (OSHA) publications are available from OSHA, 200 Constitution Avenue, NW, Washington, DC 20210, at Safety and Health Topics: Electrical—Standards Electrical Safety-Related Work Practices—Inspection Procedures and www.osha.gov/SLTC/electrical/standards.html.
[14] SAE publications are available from the Society of Automotive Engineers, 400 Commonwealth Drive, Warrendale, PA 15096, USA (http://www.sae.org/).

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SAE AMS-2418, Copper Plating (Electrodeposited) (equivalent to ASTM B734, MIL-C-14550).

SAE AMS-QQ-A-250/1A, Aluminum 1100, Plate and Sheet (superseded by ASTM B 209, Alloy 1199).

SAE AMS-QQ-A-250/2A, Aluminum Alloy 3003, Plate and Sheet (superseded by ASTM B 209, Alloy 3003).

SAE AMS-QQ-A-250/4A, Aluminum Alloy 2024, Plate and Sheet (related to ASTM B209).

SAE AMS-QQ-A-250/8B, Aluminum Alloy 5052, Plate and Sheet (related to ASTM B209).

SAE AMS-QQ-A-250/11A, Aluminum Alloy 6061, Plate and Sheet (superseded by SAE AMS 4025).

SAE AMS-QQ-A-250/12 (Edition 97), Aluminum Alloy 7075, Plate and Sheet (related to ASTM B209).

SAE AMS-QQ-B-613, Brass, Leaded/Non-Leaded; Rod/Shapes/Forgings/Flat Products with Finished Edges (Bar and Strip) (equivalent to ASTM B16).

SAE AMS-QQ-B-626D, Brass Wire (equivalent to ASTM B16).

SAE AMS-QQ-B-750, Bronze, Phosphor, Bar, Plate, Rod, Sheet, Strip, Flat Wire, and Structural and Special Shaped Sections (equivalent to ASTM B139).

SAE AMS-QQ-C-530, Copper-Beryllium Alloy Bar/Rod/Wire (Copper Alloy Numbers 172/173) (equivalent to ASTM B196).

SAE AMS-QQ-C-533 Copper-Beryllium Alloy Strip (Copper Alloy Numbers 170 and 172) (equivalent to ASTM B194).

SAE AMS-QQ-P-35, Passivation Treatments for Corrosion-Resistant Steel (cancelled February 2005, superseded by AMS2700).

SAE AMS-QQ-S-766, Steel, Stainless and Heat Resisting, Alloys, Plate Sheet (superseded by ASTM A240).

SAE AMS-QQ-W-321, Wire, Metal, Round, Non-Electrical, Copper Alloy 510 (equivalent to ASTM B134).

SAE AS39029, General Specification for Contacts, Electrical Connector, Socket, Crimp Removable.

2.1 Conventions

2.1.1 Order of precedence

Rule 2.1.1a: In the event of a conflict between the text of this document and the references cited herein (except for associated detail specifications, specification sheets, or mil-spec standards), the text of this document shall take precedence.

Rule 2.1.1b: Product qualification requirements shall be as specified herein and related to applicable specifications. In the event of any conflict between the qualification requirements and the specification documents, the latter shall govern.

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2.1.2 Reference applicability to this standard

Observation 2.1.2: This document requires a measurement means for evaluating vendor products but does not intend to impose undue rigorous demands on a commercial-off-the-shelf (COTS) product being applied to this standard. IEEE Std 1505-2010 will accept any equivalent standard to that referenced, both active or inactive, as long as the vendor applies common criteria referenced within the respective reference. The goal offered by these references is to give vendors a measurement stick for comparing its product to that of another. It is not the intent of the standard to be so rigorous that vendors qualifying their product under older standards must continue to requalify that product as the reference is superseded, modified, or discontinued. For this reason both are referenced without revision dates.

2.1.3 Responsibility of the vendor and implementer

Rule 2.1.3: The IEEE Std 1505 Working Group and IEEE Standards Organization or its respective representatives shall not accept any liability, either implied or otherwise, for vendors' products stipulating compliance to this standard. It shall be understood that integrators have full responsibility to accept product with or without understood limitations and shall have responsibility for soliciting from the supplier any and all certifications that the product meets the specifications.

3. Definitions and special terms

For the purposes of this document, the following terms and definitions apply. *The IEEE Standards Dictionary: Glossary of Terms & Definitions* should be referenced for terms not defined in this clause.[15]

ball-lock mechanism: A pin and socket type of mechanical assembly used in the receiver fixture interface (RFI) frameworks, that when latched together can withstand considerable push-pull force (maximum 159 kg [350 lb] per ball-lock assembly) applied to engage or disengage their respective attached frames.

combination frame interval: A receiver fixture interface (RFI) framework segmentation, in which a combination of a segmented frame and representative continuous frame are applied.

connector module body: A dielectric material that holds the contacts in their proper arrangement and electrically insulates them from each other and is secured to the framework as a single slot, two slot, and four slot wide application.

continuous frame interval: A receiver fixture interface (RFI) framework segmentation in which a frame can be extended to 9, 14, 24, and 29 slots without segmentation or fixture shroud spacing.

end-to-end: Description for placing receiver fixture interface (RFI) frames in an orientation that aligns the connectors in an end-to-end, stacking fashion in either a vertical or horizontal fashion.

Eurocard DIN Standard: The Eurocard Deutsches Industrie Normal (DIN) Standard (German industry connector standard organization), which establishes a signal pin contact definition and connector footprint standard for receiver fixture interface (RFI) mounting, stroke, and interchangeability for RFI connector modules and contact implementation.

fixture: An assembly that integrates a fixture frame, fixture enclosure and any other passive and active components or wiring necessary to interconnect the test system to the unit-under-test (UUT).

[15] *The IEEE Standards Dictionary: Glossary of Terms & Definitions* is available at http://shop.ieee.org/.

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fixture enclosure: Typically a metal encasement that is attached to the fixture frame to contain and protect components and cabling.

fixture frame: Receiver fixture interface (RFI) framework element that supports fixture connectors, keying, and ball-lock/release subassemblies.

fixture plug/pin header connector module: A connector module mounted to the fixture framework and typically identified as pins protruding from its housing that is encased by a shroud and recessed within the fixture to protect the pins from damage.

frame interval: The mechanical frame width dimension of 76.20 mm (3.00 in) that identifies with a segmented frame supporting four connector slots and is iterated to create continuous and combination framework.

framework structure: A contoured tongue-and-groove metal or composite structure with different spacing on the top and bottom frame outline for keying and alignment function that supports ball-lock assembly and connector mounting.

mechanical advantage: Mechanical leverage that the receiver drive system is capable of producing, which is represented as the ratio of engagement force versus the force applied by the operator on the manual handle, or motor torque applied to the drive system.

mechanical float: The ability of framework, connector housing, or the contact/termination to adjust position within fixed mechanical limits.

MIL-DTL-55302 military connector standard: A U. S. Department of Defense connector standard to meet higher environmental and electrical performance requirements for avionic board connectors based upon the commercial DIN standard.

pin contact: Male mating contact that is applied typically in the fixture module and may be terminated by direct wire, solder post for printed circuit board (PCB) mounting, or wire-wrap post.

receiver ball-lock receptacle/fixture ball-lock assembly: A mechanical assembly that, when engaged in a pin-and-socket fashion, aligns and automatically latches the receiver and fixture framework together or, when operated upon, can release the frames.

receiver fixture interface (RFI): Represents a mass electrical interconnect system that includes a test interface panel (receiver) mounted to the test system and multiple mating test interface panels (fixtures) that are uniquely designed to adapt the unit-under-test (UUT) to the receiver.

receiver fixture interface (RFI) framework: Consists of two basic mating picture frame halves that support unique multiple functions of the interface, one for the receiver and the other for the fixture.

NOTE—See also Clause 5.[16]

receiver frame: The framework assembly that is fixed to the test system and configured to serve as a common interface for multiple fixtures. It houses the receiver connectors and mechanical actuator subsystem that connects or disconnects the fixture frame to the receiver.

receiver receptacle connector module: Connector assembly that houses the receptacle contacts, which is normally mounted in the receiver in a recessed manner to protect the contact from damage and operator from potential live circuit condition.

[16] Notes in text, tables, and figures of a standard are given for information only and do not contain requirements needed to implement this standard.

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segmented framework: A receiver fixture interface (RFI) framework with a width dimension of 76.20 mm (3.00 in) that supports two ball-lock engagement points, four connector slots 60.96 mm (2.40 in) representing 4 × 15.24 mm (0.60 in) slot width, and 7.62 mm (0.30 in) space on each side of the four slots for the mating fixture protective shrouds.

side-by-side: Description for placing receiver fixture interface (RFI) frames in an orientation that aligns the connectors in a side-by-side pancake fashion in either a vertical or horizontal fashion.

slot: Receiver fixture interface (RFI) term representing a connector footprint designated for one connector type with a footprint measuring 15.24 mm (0.60 in) wide by 0.15 m (5.75 in) long, based upon a MIL-DTL-55302 military connector standard, DIN type, signal module with 200 positions (4 × 50 pin).

socket contact: Female contact that is applied protectively within the housing of a receiver module and may be terminated by direct wire, solder post for printed circuit board (PCB) mounting, or wire-wrap post.

stroke: Length of movement or travel necessary to engage or disengage the receiver fixture interface (RFI) connectors along an axial dimension of a pin-and-socket contact.

termination: Part of a contact that is attached to the printed wiring board or hookup wire.

two-part connector: Defines a mating pair of a receiver connector module and fixture connector module that contains the respective socket or pin contacts, with integral alignment keying to facilitate proper mating of the contacts.

unit-under-test (UUT): The particular equipment being tested (e.g., printed circuit board, electronic device, electrical subassembly).

3.1 Special terms

Observation: Observations spell out implications of rules and bring attention to things that might otherwise be overlooked. They also give the rationale behind certain rules so that the reader understands why the rule must be followed.

Permission: Permissions are included to clarify the areas of the specification that are not specifically prohibited. Permissions inform the reader that a certain approach is acceptable and will minimize potential problems. The word *may* is reserved for indicating permissions.

Recommendation: Recommendations consist of advice to applicants that will affect the usability of the final device. Discussions of particular hardware to enhance throughput would fall under a recommendation. These should be followed to minimize problems and to obtain optimum performance.

Rule: Rules *shall* be followed to ensure compatibility to the standard. A rule is characterized by the use of the words *shall* and *shall not.* These words are not used for any other purpose other than stating rules.

Suggestion: A suggestion contains advice that is helpful but not vital. The reader is encouraged to consider the advice before discarding it. Suggestions are included to help the novice designer with problematic areas of the design.

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4. Qualification requirements

4.1 Responsibility for inspection

Rule 4.1: Unless otherwise specified, the manufacturer shall be responsible for the performance of all inspection requirements as specified herein. The referenced specifications and standards apply to the extent that they are referenced herein. Where references overlap, are revised, or are superseded by other equivalent industry references, any one may apply to this standard.

Permission 4.1: Manufacturers may use their own or any other facilities suitable for the performance of the inspection requirements specified herein.

4.1.1 RFI qualification requirements versus standard specification relationships

Rule 4.1.1: Product qualification requirements shall be as specified herein and related to applicable specifications. In the event of any conflict between the qualifications requirements and the specification documents, the latter shall govern.

4.1.2 Reference applicability to this standard

Observation 4.1.2: This document requires a measurement means for evaluating vendor products, but does not intend to impose undue rigorous demands on a COTS product being applied to the RFI specification. This document accepts any equivalent standard (i.e., industrial, military specifications, international) to that referenced, both active or inactive, as long as the vendor applies common criteria referenced within the respective reference. The goal offered by these references is to give vendors a measurement stick for comparing their products to those of another. It is not the intent of the standard to be so rigorous that vendors qualifying product under older standards must continue to requalify that product as the reference is superseded, modified, or discontinued. For this reason both old and new standards are referenced without revision dates.

4.1.3 Inspection conditions

Rule 4.1.3: Unless otherwise specified herein, all inspections shall be performed in accordance with the test conditions specified in the general requirements of MIL-STD-202G and MIL-STD-1344A or the equivalent methods of EIA 364E.[17]

4.1.4 Test equipment and inspection facilities

Rule 4.1.4: Test and measuring equipment, ISO calibration and inspection facilities, maintained by inspection facility, shall be of sufficient accuracy, quality, and quantity to permit performance of the required inspection. The establishment and maintenance of a calibration system to control the accuracy of the measuring and test equipment (i.e., ISO/IEC 17025:2005/ANSI/NCSL Z540-1, ISO 10012-1—Part 1, or comparable standards) shall be required.

4.1.5 Responsibility of the vendor and implementer

Rule 4.1.5: It shall be understood that integrators have full responsibility to accept product with or without understood limitations and shall have responsibility for soliciting from the supplier any and all certifications that the product meets the specifications.

[17] Information on references can be found in Clause 2.

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4.2 General requirements

4.2.1 Statistical process control (SPC)

Recommendation 4.2.1: It is recommended that the manufacturer implement and use SPC techniques in the manufacturing process for parts covered by this specification. The SPC program should be developed and maintained in accordance with guidelines of EIA 557B. Where SPC cannot be utilized because of non-continuous production requirements, a lot sampling plan for inspection in accordance with group A lot and sample size with $c = 0$ is recommended. The SPC and $c = 0$ programs may be documented and maintained as part of the overall reliability assurance program as specified in EIA 557B.

4.2.2 Materials

Rule 4.2.2: Suppliers shall identify materials used in the manufacturing of the IEEE 1505 products to the purchaser. When a definite material is not specified, a material shall be used that enables the connectors and accessories to meet the form, fit, function, and performance requirements of this document (see 5.12). Acceptance or approval of any constituent material by the buyer shall not be construed as a guaranty of the acceptance of the finished product from the manufacturer.

4.2.2.1 Reference materials, platings and processes

Rule 4.2.2.1a: The identified reference materials, platings, and processes described in 4.2.2, 5.3, 5.4, 5.5, 5.6, and 6.12 shall be used to enable framework and connectors manufactured to this document to mate to similar industry standard or government-specified framework and connector systems with minimal problems related to electrochemical contamination of critical electrical or mechanical interfaces or generation of incompatible mechanical interface surface wear products.

Permission 4.2.2.1: The manufacturers of framework and connectors supplied to this standard may use alternate recognized industry standard materials, platings, and processes from those identified in 4.2.2, 5.3, 5.4, 5.5, 5.6, and 6.12 of this specification. However, use of alternate materials, platings, and processes shall be coordinated with the respective qualifying activity as part of the qualification process.

Rule 4.2.2.1b: Use of alternates to those referenced guidance items by the supplier shall not result in inferior short- or long-term performance or reliability of supplied framework and connectors as compared with framework and connectors manufactured using the referenced materials, platings, or processes. Short- or long-term failures or reliability problems due to use of these alternates shall be the responsibility of the supplier.

4.2.2.2 Recycled, recovered, or environmentally preferable materials

Recommendation 4.2.2.2: Recycled, recovered, or environmentally preferable materials should be used to the maximum extent possible provided that the material meets or exceeds the operational and maintenance requirements, and promotes economically advantageous life-cycle costs.

4.2.2.3 Nonmagnetic materials

Rule 4.2.2.3: All direct electrical interconnect/contact assembly parts shall be made from materials which are classed as nonmagnetic (permeability 2μ using indicator in accordance with ASTM A342).

4.2.2.4 Plastic molded materials

Rule 4.2.2.4: Unless otherwise specified (see 6.12), the connector molded body material shall conform to:

a) SDG-F or GDI-30F in accordance with ASTM D5948-05E1 (see 4.2.2) *or*

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b) Type TPES013G30 in accordance with ASTM D5927-09 *or*

c) PPS000G40A30330E1F01Y1 1 in accordance with ASTM D4067-03 *or*

d) Type MIL-M-24519E/GPT-30F or GST-40F

e) Reground materials shall not be used.

4.2.3 Metals

4.2.3.1 Aluminum

Rule 4.2.3.1: Where applicable, aluminum shall be as specified in SAE-AMS-QQ-A-250/1A (Aluminum 1100), SAE-AMS-QQ-A-250/2A (Alloy 3003), SAE-AMS-QQ-A-250/4A (Alloy 2024), SAE-AMS-QQ-A-250/8B (Alloy 5052), SAE-AMS-QQ-A-250/11A (Alloy 6061), or SAE-AMS-QQ-A-250/12 (Alloy 7075), and anodized to meet the requirements of MIL-F-14072.

4.2.3.2 Corrosion-resistant steel

Rule 4.2.3.2: Where applicable, corrosion-resistant steel shall be 300 series, low magnetic permeability in accordance with SAE-AMS-QQ-S-763, ASTM A581, ASTM A582M-05, or ASTM A484M-03 and passivated in accordance with SAE-AMS-QQ-P-35, or to finish E300 as specified in MIL-F-14072.

4.2.3.3 Socket contacts, hermaphroditic contacts, and contact terminations

Rule 4.2.3.3: Socket contacts, hermaphroditic contacts, and contact terminations shall be copper-nickel-tin alloy C72900 per ASTM B740-02, or beryllium copper as specified in ASTM B194, ASTM B196, ASTM B197, or C17500 in accordance with ASTM B441-04, or phosphor bronze in accordance with ASTM B103 or ASTM B139M-07, or contact terminations of brass alloy in accordance with ASTM B16 or ASTM B134, or thermocouple materials in accordance with SAE-AS39029, or gold plated per 4.2.3.6.

4.2.3.4 Pin contacts and contact terminations

Rule 4.2.3.4: Pin contacts and contact terminations shall be:

a) Copper-nickel-tin alloy C72900 as specified in ASTM B740-02 *or*

b) Brass as specified in ASTM B16, ASTM B36M-08A, ASTM B134, or ASTM B121 *or*

c) Phosphor bronze, in accordance with ASTM B139 or beryllium copper as specified in ASTM B 159, ASTM B194, ASTM B196, ASTM B197, or C18700 in accordance with ASTM B301M-08 *or*

d) Thermocouple materials in accordance with SAE-AS39029 or gold plated per 4.2.3.6.

4.2.3.5 Connector guide pins and guide bushings

Rule 4.2.3.5: Guide pins and guide bushings shall be:

a) Free-cutting, half-hard brass as specified in ASTM B36M-08A or ASTM B121M *or*

b) Copper alloy as specified in ASTM B134, or ASTM B159, or ASTM B206M *or*

c) Stainless steel as specified in SAE-AMS-QQ-S-763 or ASTM A582M-05 *or*

d) Alternate acceptable materials, which shall be of appropriate physical performance to provide a noncorrosive, nongalling condition and provide adequate wear characteristics in accordance with ASTM-A240, or similar nickel-based materials.

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4.2.3.6 Plating

Rule 4.2.3.6: Unless otherwise specified (see Clause 6, Annex A, and Annex B), contacts shall be gold plated 76 µm (30 µin) minimum, in accordance with ASTM B488-01 (2006) Type II, Class 1.27, Grade C, or the equivalent SAE AMS 2422 sections, over suitable underplate (see 4.2.3.3).

4.2.3.7 Nickel underplate

Rule 4.2.3.7: Nickel underplate shall be Class 2, 76 µm (30 µin) to 381 µm (150 µin), as specified in SAE-AMS-QQ-N-290.

4.2.3.8 Localized finish

Rule 4.2.3.8: Localized systems such as selective plating, welded dot, etc., are permitted in lieu of overall plating providing the following conditions are met:

a) Contact engagement end shall be gold plated to 0.076 mm (30 µin) minimum in accordance with ASTM B488-01 (2006), Type II, Class 1.27, Grade C, over nickel underplate per 4.2.3.8.

b) Contact termination end plating (solderless wrap) shall be tin-lead (95%-5%) composition in accordance with SAE-AMS-81728, 254 µm (100 µin) to 762 µm (300 µin) thick over nickel underplate in accordance with 4.2.3.8.

c) Contact termination end plating (crimp), tin-gold (96%-4%) composition, 0.076 mm (30 µin) minimum over nickel underplate in accordance with 4.2.3.8, or tin-lead (955%-5%) composition 254 µm (100 µin) minimum thickness in accordance with SAE-AMS-81728 over nickel underplate in accordance with 4.2.3.8. Solder dipping is permitted, providing it meets procedures and requirements of MIL-STD-202G, Method 208.

d) Nonfunctional areas need not be overplated, provided they have a minimum thickness of 127 µm (50 µin.) of nickel in accordance with SAE-AMS-QQ-N-290, Class 2.

Permission 4.2.3.8: When contacts have been provided in strip form, the absence of plating in the area where the contact was removed from the strip is acceptable provided it is in a nonfunctional area and any corrosion formed as a result of salt spray testing does not creep into the contact mating area.

4.2.4 Restricted materials

4.2.4.1 Flammable, explosive, or toxic

Rule 4.2.4.1: All material shall be nonflammable, nonexplosive, and nontoxic over the operating temperature range (5.21.1, 6.20.1).

4.2.4.2 Corrosion resistance

Rule 4.2.4.2: The framework, connectors, and accessories shall be of corrosion-resistant materials or treated to prevent corrosion.

4.2.4.3 Ferrous

Rule 4.2.4.3: All material containing more than 5% iron shall not be used for current carrying parts.

4.2.5 Dissimilar metals

Rule 4.2.5: Where dissimilar metals are used in intimate contact with each other, protection against electrolysis and corrosion shall be provided by means of zinc plating, passivation, coatings, or other

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inhibitors. Dissimilar metals shall be as defined in MIL-STD-889B. Dissimilar metals such as brass, copper, or steel (except corrosion-resisting steel, passivated in accordance with 4.2.3.2) shall not be used in intimate contact with aluminum or aluminum alloy.

4.2.6 Fungus resistance

Rule 4.2.6: Finishes and materials used in the construction of all interface components shall be fungus inert in accordance with MIL-STD-810F.

4.3 Qualification inspections

Rule 4.3: Qualification inspections shall be supported by verifying data from the manufacturer that the materials listed in Table 1, used in fabricating the framework, connectors, and accessories, are in accordance with the applicable IEEE 1505 conformance definitions, product drawings, and/or referenced specifications and maintained under equivalent ISO-9001 quality assurance provisions or otherwise agreed by the customer's quality authority where noncompliance occurs.

4.4 Inspection conditions

Rule 4.4: Unless otherwise specified herein, all inspections shall be performed in accordance with the test conditions specified or normal manufacturing expected conditions, whichever is more absolute. All products per advertised specifications shall be maintained under ISO-9000 quality assurance provisions or otherwise noted and agreed by the customer's quality authority.

Table 1—Qualification inspection

Component material	Defined in subclause	Applicable referenced specifications
Plastic, molded materials	5.2, 5.3, 5.4	SDG-F, GDI-30F, MIL-M-24519E/GPT-30F, MIL-M-24519E/GST-40F (equivalent to ASTM-D5927-09/D5948-05E1), ASTM-D4067-03
Framework/connector metal hardware	5.7, 5.10, 5.11	
Copper nickel alloy	5.3, 5.4, 6.7, 6.8	ASTM B740-02, SAE-AMS-2418, and SAE-AMS-QQ-N-290
Phosphor bronze/beryllium copper	5.3, 5.4, 6.7, 6.8	SAE-AMS-QQ-B-750, SAE-AMS-QQ-C-530, or ASTM B139M-07/B194, SAE-AMS-QQ-C-533
Copper alloy wire	5.3, 5.4, 6.7, 6.8	SAE-AMS-QQ-W-321, ASTM B206M/B740-02

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Table 1–Qualification inspection *(continued)*

Component material	Defined in subclause	Applicable referenced specifications
Brass (leaded and nonleaded)	5.3, 5.4, 5.5; 6.7, 6.8	SAE-AMS-QQ-B-626D and SAE-AMS-QQ-B-613, ASTM B121, ASTM B134
Aluminum	5.3, 5.4, 5.5; 6.7, 6.8	SAE-AMS-QQ-A-250/1A,/2 A,/4 A,/8B,/11A, and /12; MIL-F-14072, ASTM-B209-07
Steel	5.3, 5.4, 5.5; 6.7, 6.8	SAE-AMS-QQ-P-35, SAE-AMS-QQ-S-763, SAE-AMS-QQ-S-766, (or equivalent to ASTM A240, ASTM A666-00, ASTM A693-06, and ASTM-A967-1999E1), and ASTM-A581/582/484
Dissimilar metals	5.5, 5.7; 6.5	MIL-STD-889B
Fungus resistance	5.3, 6.6	MIL-HDBK-454B/4
Framework/connector body	5.2, 5.3, 5.5, 5.9, 5.10; 6.7, 6.8	FED-STD-H28

4.5 Qualification inspection

Rule 4.5: Qualification inspection shall be performed on sample units produced with equipment and procedures normally applied in production.

4.5.1 Sample

Rule 4.5.1: Mating pairs of the connector product samples to the required sample size shall be inspected per respective testing requirements per 4.6 and related specifications.

4.5.1.1 Sample inspection for RFI product

Rule 4.5.1.1: To qualify normally disassembled product elements described by applicable connector and contact clause specification (see Clause 7 through Clause 12), each supplier shall perform compliance testing to the product level it supports (i.e., contacts only to contact specification that it advertises) or certify in accordance with the inspection criteria in Table 2, Table 3, and Table 4.

4.5.1.2 Sample size and measurements

Rule 4.5.1.2: The sample size of connectors shall be in accordance with respective product element specifications described in Clause 6. All framework sample units shall undergo full inspection requirements in accordance with 4.6. For connector sample units, a total of 15% of the contact positions shall be measured per connector sample for each subgroup. For connectors with 13 or fewer contacts, all positions shall be measured. This shall apply to the requirements as specified in 4.6. The same contact positions shall be monitored throughout the test sequences.

4.5.2 Inspection routine

Rule 4.5.2: Sample units shall be subjected to the inspections specified in Table 2, Table 3, and Table 4. All RFI framework and connector assembly sample units shall be subjected to the visual, dimensional, mechanical, and environmental inspections in accordance with the inspection acceptance criteria in Table 2, Table 3, and Table 4. Connector samples shall further undergo testing in accordance with the connector inspection acceptance criteria in Table 3.

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4.5.3 Failures

Rule 4.5.3: All failures shall be documented and reliability data supplied when requested by a purchaser to verify product conformance to this document, or stipulate any deviations to that stated.

Recommendation 4.5.3: MIL-HDBK-217F is the recommended resource for determining reliability for the respective product being supplied under this standard.

Suggestion 4.5.3: Failure history collection is suggested by all product manufacturers, to support goals of continuous improvement/product reliability enhancement.

Table 2—Framework and connector mechanical inspection acceptance criteria

Inspection requirement	Defined in subclause	Method subclause
Visual and mechanical	5.6–5.22; 6.7	4.6.1
Interchangeability and engagement forces[a]	5.14, 5.16, 6.9, 6.11, 6.12	4.6.2.1
Mating and unmating conformance	5.16.3, 5.18, 6.11, 6.12	4.6.2.2, 4.6.2.3
Durability cycling	5.8.2, 5.19, 6.12, 6.19	4.6.2.4, 4.6.2.7
Connector/contact conformance[a]	6.13	4.6.2.4, 4.6.2.5
NOTE—All electrical tests may be performed on same sample(s) in one test group. All mechanical tests may be performed on an additional sample(s) in one test group.		

[a]When applicable (see 4.3 and Table 1).

4.6 Method of examination and test

4.6.1 Visual and mechanical examination

Rule 4.6.1a: An examination shall be made to determine compliance with each of the requirements of 4.3.

Table 3—Connector electrical inspection acceptance criteria

Inspection requirement	Defined in subclause	Method subclause
Contact resistance	6.14, 6.23	4.6.3.1
Electrical characteristics	6.4, 6.7	4.6.3.9
Dielectric withstanding voltage[a] (sea level) 5 s exposure	5.8.1, 6.16	4.6.3.3
Low level contact resistance	6.17	4.6.3.4
Insulation resistance[a]	5.18.2, 6.18	4.6.3.5
Crimp/Wire-wrap termination	7.3.11	4.6.3.6
Crimp tensile strength	6.24	4.6.3.7
Contact retention	6.15	4.6.3.2
Solderability (contacts only)	6.22	4.6.3.8

[a]Applicable to connectors furnished with assembled contacts.

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Table 4—Framework and connector environmental inspection acceptance criteria

Inspection requirement	Defined in subclause	Method subclause
Operating temperature	5.21.1, 6.20.1	4.6.4.1
Temperature cycling	5.21.2, 6.20.2	4.6.4.2
Humidity	5.21.3, 6.20.2	4.6.4.3
Vibration	5.21.5, 6.20.3	4.6.4.4
Shock (specified pulse)	5.21.6, 6.20.6	4.6.4.5
Salt spray	5.21.7, 6.20.7	4.6.4.6
Solvent resistance/fluid immersion	5.21.8, 6.20.8	4.6.4.7
Flammability	5.21.9, 6.20.9	4.6.4.8

Rule 4.6.1b: Framework, connectors and accessories shall be visually inspected in such a manner as to be uniform in quality and shall be free from burrs, crazing, cracks, voids, pimples, chips, blisters, pinholes, sharp cutting edges, and other defects that adversely affect life, serviceability, or appearance.

4.6.2 Framework and connector mechanical specification conformance testing

4.6.2.1 Inspection for Interchangeability

Rule 4.6.2.1a: All IEEE 1505 products shall satisfy interchangeability requirements between common or multiple-manufacturer entities by meeting the following:

a) Physical configuration and dimensional measurements of 4.3

b) Related Clause 5 (framework) and Clause 6 (connector) specifications

c) Qualification inspections, as referenced in Table 3

d) Subsequent applicable requirements in accordance with Methods 2013.1 and 2014 of MIL-STD-1344A or equivalent methods of EIA 364E

Rule 4.6.2.1b: The following dimensions shall be gauged or measured to determine conformance to the physical interchangeability requirements of applicable specifications (see 4.3). When a listed dimension is not within specified dimensions and tolerances as defined by this specification, it shall be considered a major defect. Major defects are as follows:

a) External and internal dimensions of cases, covers, and inserted assemblies, when such dimensions affect mating parts.

b) Dimensions of cavities, when such dimensions affect insertion of items.

c) Location of connectors, locking pins, fasteners, adequacy of connector float/mounting screw implementation, and other mountings, as applicable, which receive mating parts of plug-in assemblies and major units, and location of the mating parts on the plug-in assembly or major unit.

Recommendation 4.6.2.1: It is recommended that manufacturers utilize opportunities to mate/unmate products with other manufacturers' products to verify that compatibilities exist. Integrators and/or users may implement their own respective tests with multiple vendors' products to qualify source acceptance.

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4.6.2.2 Mating framework conformance specification testing

Rule 4.6.2.2a: Each manufacturer shall conduct and comply with the mating framework conformance specification as established by Clause 5 and test in accordance with Method 2013.1 of MIL-STD-1344A, EIA 364E, or equivalent methods, to verify the specification is being met. An applicable defined/measured compliant mating receiver/fixture test specimen, per 4.6.2.2, is required to perform this test.

Rule 4.6.2.2b: Each manufacturer, or third-party test facilitator, shall conduct mating receiver/fixture conformance tests in accordance with Method 2013.1 of MIL-STD-1344A, EIA 364E, or equivalent methods, to verify 5.8 and 5.16 are being met. The test requires that a test specimen receiver or fixture be applied to a compliant mating frame, with a minimum engagement load of 75% of the advertised engagement capability for a period of 5 s, through a 500-cycle exercise, without causing the following:

a) Mechanical interference, binding, push-back by ball-lock spring actions, and/or visible wear to the receiver or fixture

b) Misalignment of greater than 0.51 mm (0.02 in) to preset alignment connector contact points (minimum of five contact points, four corners and center), per 76.2 mm (3.0 in) increment of the framework

c) Failure to engage, maintain engagement under 75% load of maximum pin load in quantity or force, and disengage the fixture and all related ball-lock mechanisms from their respective receiver receptacles

d) Visible connector gap due to coplanar distortion, ball-lock non-engagement, or other mechanical instability that results in contact electrical “opens” or contact electrical/mechanical resistance beyond the specification

e) Failure to maintain parallel relationships between the receiver and fixture framework that would cause a greater than 2.032 mm (0.080 in) gap between facing surfaces (see 5.10), contact electrical excessive resistance, or contact electrical opens

f) Force being applied to the engagement handle by the operator to exceed 20 kg (40.1 lb), as measured at the end of the handle

g) Other detrimental impact to mating elements

A minimum sample of two units shall be measured to the conformance test.

Rule 4.6.2.2c: Each manufacturer, or third-party test facilitator, shall conduct maximum fixture support weight tests to verify that 5.19 is being met. The test shall require that a compliant test specimen receiver and specified weighted fixture [fixture weight is calculated be applying the specified maximum weight at the center point of the fixture width at 381 mm (15 in) from the face of the fixture framework], with a minimum engagement load of 75% load of maximum pin load in quantity or force, be engaged for a period of 10 s through a 100-cycle exercise, without causing any conditions specified in Rule 4.6.2.2b.

Rule 4.6.2.2d: Maximum fixture support weight rating of framework shall be as specified based upon combined drive and ball-lock engagement capability (holding force) not to be less than 45 kg (100 lb) per ball-lock, reflecting the amount of fixture weight that can be both supported in a cantilevered fashion while also meeting a specified engagement resistance specifications as tested in accordance with 4.6.2.

Rule: 4.6.2.2e: Fixture footprints shall not exceed dimensions described in 5.20 (see Figure 35) that would intrude on the (right side) manual handle and (bottom) lower fixture support areas.

4.6.2.3 Mating contact/receptacle conformance specification testing

Rule 4.6.2.3a: To meet IEEE 1505 requirements, each manufacturer shall conduct and comply with a mating contact/receptacle conformance specification established within each respective connector/contact

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specification described in Clause 7 through Clause 12. An applicable defined/measured compliant mating pin or receptacle contact test specimen per Clause 7 through Clause 12 is required to perform this test.

Rule 4.6.2.3b: Each manufacturer, or third-party test facilitator, shall conduct mating contact/receptacle conformance tests as described herein, in which compliant test contact pins are applied to sample contact sockets of the connector, or the reverse for a period of 10 s/cycle, through a 500-cycle exercise, without causing the following:

a) Visible wear to the socket or pin

b) Loss of memory to spring-loaded receptacle features to maintain surface contact

c) Nonconformance to mechanical engagement resistance (per 6.17) across mating surfaces

d) Nonconformance to electrical resistance or reduced parametric performance (per 6.19) across mating surfaces

e) Mechanical pushback (greater than 15%) within connector housing cavity

f) Other detrimental impact to mating elements

A minimum sample of seven mating connector sets shall be measured to satisfy conformance tests.

Rule 4.6.2.3c: Each manufacturer or third-party test facilitator shall conduct mating connector conformance tests as described in Rule 4.6.2.3b. During 500 cycles of insertion and withdrawal, the force required to fully insert and withdraw a fully populated connector plug from the mating receptacle shall be measured after 25, 100, 250, and 500 cycles. Each fully populated connector plug and receptacle so mated shall be considered as one test specimen, with a minimum of three mated pairs being required to satisfy conformance tests. The measuring equipment shall conform to the following specifications:

a) Axis of insertion of the pin contacts and mating receptacle contacts or hermaphroditic contacts as applicable shall coincide during insertion and withdrawal.

b) Speed of insertion of the plug into the receptacle contacts shall not exceed 6 cycles per minute for constant speed machines, or the rate of loading shall not exceed 80 lb per min for constant-rate-of-force machines.

c) Scale mechanisms shall have no dashpots or other damping devices.

d) Scales shall be calibrated in 56.7 g (0.13 lb) steps or less and shall be accurate to within 56.7 g (0.13 lb).

NOTE—When mating and unmating tests are required by another test such as contact life, the preconditioning cycles are not required.

4.6.2.4 Oversized pin exclusion (pins only) test

Rule 4.6.2.4: The oversized pin exclusion (contact pins only) requirement, which determines RFI product pin dimension conformance, shall be met by inserting a test sample pin into the mating end of the socket test fixture that excludes the entry of a test sample pin larger than the allowable maximum pin dimensions, as specified in Clause 6 and related detailed specifications in Clause 7 through Clause 12.

4.6.2.5 Oversized pin/probe damage socket test

Rule 4.6.2.5: The *oversized pin/probe damage socket test* requirement determines RFI connector socket/receptacle test sample ability to maintain dimension conformance when an oversized pin or probe is inserted in accordance with Method 2006-1 of MIL-STD-1344A, EIA 364E, or equivalent methods. The connector and mating socket contact entry opening shall prevent an oversized pin or probe that exceeds the tolerances, as specified in Clause 6 and related annex descriptions, from entering the socket. The

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receptacle/socket test sample and oversized pin shall be fixtured to verify that concentric relationships are maintained during the insertion test.

4.6.2.6 Framework durability cycling

Rule 4.6.2.6a: To meet IEEE 1505 requirements, each manufacturer shall subject the test specimen receiver and fixture to a *durability cycle test* in accordance with Method 2016 of the MIL-STD-1344A, EIA 364E, or equivalent methods. A minimum durability cycle objective of 25 000 repetitions shall be used. Each manufacturer or third-party test facilitator shall establish a defined mechanical/electrical setup to provide a comprehensive test and data collection that verifies the manufacturer's product specifications and meets minimum requirements of IEEE Std 1505-2010. The framework cycle test shall validate reliability of the framework to achieve its advertised capabilities under subsequent MIL-STD-1344A requirements.

Rule 4.6.2.6b: For the framework durability cycle test of fixture engagement, insertion, and withdrawal, the force shall be sufficient to fully insert and withdraw from the receiver. If the force is manually applied, it shall be measured at the operating handle and shall not exceed 16 kg (35 lb). Each plug and receptacle so mated shall be considered as one test specimen when further testing of the plug or receptacle is indicated. The measuring equipment shall conform to the following specifications:

a) Axis of insertion of the pin contacts and mating receptacle contacts or hermaphroditic contacts as applicable shall coincide during insertion and withdrawal.

b) Speed of insertion of the plug into the receptacle contacts shall not exceed six cycles per minute for constant speed machines, or the rate of loading shall not exceed 80 lb per min for constant-rate-of-force machines.

c) Scale mechanisms shall have no dashpots or other damping devices.

d) Scales shall be calibrated in 56.7 g (0.13 lb) steps or less and shall be accurate to within 56.7 g (0.13 lb).

4.6.2.7 Connector durability cycling

Rule 4.6.2.7a: To meet IEEE 1505 requirements, each manufacturer shall conduct and comply with an mating contact/receptacle conformance specification established within each respective connector/contact specification described in Clause 6 through Clause 12; MIL-STD-1344A, Method 2002.1; EIA 364E; or equivalent methods.

Rule 4.6.2.7b: Each unit shall be subjected to 10 000 insertion and withdrawal cycles. The following items shall apply:

a) Axis of the pin contacts and mating receptacle contacts shall coincide during insertion and withdrawal.

b) Durability cycle rate shall not exceed six cycles per minute.

c) Contact electrical resistance continuity measurements shall be measured at each 2500-cycle interval to 5% of the pins in equal pattern across the beam of the mating connectors, maintaining requirements established in 6.19.

d) Connector mating and unmating forces shall be measured and maintained in accordance with respective connector requirements (see 6.17 and connector detailed specifications in Clause 7 through Clause 12).

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4.6.3 Connector electrical specification conformance testing

Rule 4.6.3: Advertised connector electrical specifications by manufacturers shall be supported by documented test results conducted by the manufacturer, or third-party test labs in accordance with Clause 6, and the respective connector detailed specifications in Clause 7 through Clause 12).

4.6.3.1 Contact electrical resistance

Rule 4.6.3.1: The *contact electrical resistance* shall be measured individually between each mated pair of contacts. A minimum of six mated pairs of contacts shall be measured on each test specimen, in accordance with Method 3004 of MIL-STD-1344A, EIA 364E, or equivalent methods.

a) **Method of connection:** Attach current-voltage leads at extreme ends of contacts. For crimp-type contacts, attach current-voltage leads to wires at closest point to contact without touching contact.

b) **Test current:** See respective contact rated current (see Clause 7 through Clause 12).

4.6.3.2 Contact retention/float within connector housing

Rule 4.6.3.2: Connectors shall be tested to meet minimum contact retention requirements per Method 2007 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details and exceptions shall apply:

a) **Number of samples:** A minimum of seven contacts per test specimen shall be tested.

b) **Applied axial load:** 1 lb/s until the load specified in individual specification supplements has been reached. Maintain load for 5 s. (When hookup wire is used, the wire shall be large enough to withstand the applied load).

c) **Maximum allowable contact displacement:** During application of specified force and after removal of specified force, per respective contact displacement-float tolerance (see the connector specifications in Clause 6 through Clause 12).

d) **Axial direction:** Straight.

e) **Removable type contacts:** Shall withstand an axial load (see 4.3) applied in the normal removal direction after 10 insertions and withdrawals from the same contact hole.

4.6.3.3 Dielectric withstanding voltage

Rule 4.6.3.3: Mated connectors shall be tested to meet dielectric-withstanding-voltage requirements in accordance with Method 3001 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details and exceptions shall apply:

a) **Preparation:** Mated, and may be mounted to printed wiring board.

b) **Magnitude of test voltage:** As specified (see Clause 6 through Clause 12).

c) **Nature of potential:** AC (rms).

d) **Duration of application of test voltage:** 60 s.

e) **Points of application of test voltage:** Between the closest contacts and between the contacts and all other metallic parts connected together.

f) **Method of connection of test voltage to specimen:** Affix test probes to terminations described in 4.6.3.1 by clips or solder.

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4.6.3.4 Low-Level circuit

Rule 4.6.3.4: A minimum of seven mated pairs of contacts on each test specimen shall be individually measured in accordance with Method 3002.1 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) Method of connection: Attach current-voltage leads at extreme ends of contacts. For crimp-type contacts, attach current-voltage leads to wires, at closest point to contact without touching contact.

b) Not to exceed 100 mA at 20 mV dc open circuit.

c) Respective specification measured as maximum contact resistance level that is described in associated maximum contact resistance tables.

4.6.3.5 Insulation resistance

Rule 4.6.3.5: Mated connectors shall be tested in accordance with Method 3003 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details and exceptions shall apply:

a) Special preparation:

   1) The connector shall be mated and may be mounted on a printed wiring board.

   2) The printed wiring board may be conformal coated or otherwise protected.

b) Point of measurement: Check between pins and hardware, between pin and pin, and between pins and shell (on shell-constructed connectors).

4.6.3.6 Crimp/wire-wrap termination

Rule 4.6.3.6: Each terminal, except wire-wrap post and crimp, shall be subjected to Method 208 of MIL-STD-202G.

4.6.3.7 Crimp tensile strength (applicable to crimp contacts only)

Rule 4.6.3.7: The test shall be performed in accordance with Method 2003 of MIL-STD-1344A, EIA 364E, or equivalent methods. Samples for test shall be placed in a standard tensile testing machine and the load applied at an approximate rate as specified to pull the wire out of the sample or break the wire sample. Values shall be in accordance with the respective connector clauses (Clause 6 through Clause 12). Note that these values are for MIL-DTL-16878 wire used in conjunction with the proper crimp contact. Ten samples of each wire size (both pin and receptacle types) shall be tested.

4.6.3.8 Solderability

Rule 4.6.3.8: All connectors with solder terminations shall be tested in accordance with Method 210 of MIL-STD-202G, Condition C, except connectors with solder cup terminations, which shall be tested in accordance with the following details:

a) The applicable wire size properly prepared for the solder cup size shall be inserted into the contact termination. A minimum of seven contacts shall be tested.

b) An appropriately prepared resistance soldering iron with an appropriate tip shall be applied to the lower portion of the solder cup configuration where the wire enters the termination.

c) The solder shall be applied in the normal manner.

d) The resistance soldering iron shall be applied to the system. The wattage shall be adjusted as to allow a proper solder fillet to be formed or for a 4 s minimum time limit, whichever is more.

e) After application, the soldering iron shall be removed and a visual/mechanical inspection performed.

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f) Visual inspection shall be at magnification power times 10. The connector shall show no evidence of distortion or damage to any area of the connector housing. The contact shall meet the contact retention requirement The contact shall not interfere with normal floating conditions as applicable and shall meet applicable location dimensions.

4.6.3.9 Contact electrical characteristics

Rule 4.6.3.9a: Coaxial standing wave ratio (SWR) measurements in accordance with Method 3005 of MIL-STD-1344A, EIA 364E, or equivalent methods, if applicable, shall be applied on all coaxial connector assemblies and included in any connector specification and contact rating.

Rule 4.6.3.9b: Coaxial radio frequency (RF) transmission loss, leakage, and RF high potential withstanding voltage measurements, in accordance with 4.6.12, 4.6.13, and 4.6.16 of MIL-C-83517, respectively, shall be included in any coaxial connector specification and contact rating.

Rule 4.6.3.9c: Power current rating measurements, in accordance with IEC 60309-1, shall be included in any power connector specification and contact rating.

Rule 4.6.3.9d: Power creepage/dielectric resistance measurements, in accordance with Method 3003.1 of MIL-STD-1344A, EIA 364E, or equivalent methods, shall be included in any connector specification and contact rating.

4.6.4 Environmental test compliance

4.6.4.1 Operating Temperature

Rule 4.6.4.1: Conformance to the temperature cycling requirements per applicable specification supplements (see 4.3) shall constitute verification of the product operating temperature.

4.6.4.2 Temperature cycling

Rule 4.6.4.2: Mated connectors shall be tested in accordance with Method 1003 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) **Special mounting:** The connector halves shall be mounted on mounting framework.

b) **Test condition:** A, except that the minimum temperature shall be 10 °C +0/–5 °C and the maximum temperature shall be 50 °C +3 /–0 °C.

c) **Test measurement:** The connector shall be capable of mating and unmating the temperature extremes (force shall not be monitored) during the fifth cycle.

d) **After test examination:** Connectors shall be examined for evidence of cracking, crazing, or other physical damage, and the contact resistance shall be measured in accordance with 4.6.3.1.

4.6.4.3 Humidity

Rule 4.6.4.3: Connectors shall be tested in accordance with Method 1002, Type II of MIL-STD-1344A, except steps 7a and 7b shall not be required. Alternatively, equivalent methods of EIA 364E shall be used. The mated pairs shall be connected as specified in 4.6.2.3. The printed wiring board may be conformal coated or otherwise protected. The loading voltage shall be 100 V dc. Insulation resistance shall be measured in accordance with 4.6.3.5, upon completion of step 6 of the final cycle, after removal of surface moisture from connector.

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4.6.4.4 Vibration

Rule 4.6.4.4a: Framework shall be tested in accordance with Method 2005 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) **Mounting:** Specimen mating receiver/fixture connectors shall be mounted in a fully populated four-slot receiver and fixture configuration with the receiver framework mounted with standard mounting screws to the receiver mounting plate, which is firmly mounted on the vibration table.

b) **Stabilization:** Arrangement of a fully mated receiver and fixture shall be provided, which prevents the mated connectors from mechanically separating, or electrically opening during vibration tests. The resisting medium shall contact the receiver framework mounting surfaces on the test jig only, and no initial load shall be imparted to the connector.

c) **For connector saver connectors:** The mated pairs shall be mounted per integration specifications.

d) **Monitoring circuit:** Shall be provided to detect any interruption greater than 1 µs.

e) **Electrical load condition:** 100 mA.

f) **Test condition:** Frequency requirement for 5 Hz to 55 Hz at a maximum of 29.4 m/s for vibration. (6.86 m/s at 5 Hz to 15 Hz, 12.74 m/s at 16 Hz to 25 Hz, 29.4 m/s at 26 Hz to 55 Hz).

g) **After test examination:** Connectors' mounting hardware shall be visually examined for loosening, fracture, or other deterioration.

Rule 4.6.4.4b: Mated connectors shall be independently tested in accordance with Method 2005 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) **Stabilization:** Arrangement shall be provided as indicated on Figure 2 of Method 2005 of MIL-STD-1344A, EIA 364E, or equivalent methods, such that a resisting force shall exist through a compliant material (rubber with a Shore A durometer of about 25), which prevents the mated connectors from separating during vibration and shock. The resisting medium shall contact the top and side surfaces on the test jig only, and no initial load shall be imparted to the connector other than the weight of the test jig.

b) **For straight-through connectors:** A mated pair shall be mounted an individual parallel wiring boards and secured by bolts and standoffs as indicated on Figure 3 of Method 2005 of MIL-STD-1344A, EIA 364E, so that the distance between the wiring boards is equal to the height of the assembled connectors.

c) **Monitoring circuit:** Shall be provided to detect any interruption greater than 1 µs.

d) **Electrical load conditions:** 100 mA

e) **Test condition:** III

f) **After test examination:** Connectors and mounting framework shall be visually examined for loosening, fracture, or other deterioration.

4.6.4.5 Shock (specified pulse)

Rule 4.6.4.5: Mated four-slot receiver and fixture framework with full population of specimen mating connectors shall be tested in accordance with Method 2004 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) Mounting method and accessories: In accordance with item a) in 4.6.4.4 and suitable monitoring circuit to detect any interruption greater than 1 µs.

b) Test condition: Pulse requirement for 5 ms of 49 m/s for shock.

c) Number of blows: One blow in both directions along each of three mutually perpendicular axes for a total of six shocks.

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d) Test current: 100 mA

e) After test examination: Connectors and mounting framework shall be visually examined for loosening, fracture, or other deterioration.

4.6.4.6 Salt spray (corrosion)

Rule 4.6.4.6: Mated connectors shall be tested in accordance with Method 1001 of MIL-STD-1344A, EIA 364E, or equivalent methods. The following details shall apply:

a) Applicable salt solution in accordance with MIL-STD-1344

b) Test condition: B

4.6.4.7 Solvent resistance and fluid immersion

Rule 4.6.4.7: Mated connectors shall be tested in accordance with Method 1016 of MIL-STD-1344A, EIA 364E, or equivalent methods.

4.6.4.8 Flammability

Rule 4.6.4.8: Mated connectors shall be tested in accordance with Method 1012 of MIL-STD-1344A, EIA 364E, or equivalent methods.

4.6.4.9 Human Safety

Rule 4.6.4.9: Mechanical and electrical components shall be reviewed and marked accordingly per the following Occupational Safety and Health Administration (OSHA)[18] regulations governing human safety and use of IEEE 1505 apparatus during operation. These include the following:

a) OSHA Enforcement of the Electrical Power Generation, Transmission, and Distribution Standard, CPL 02-01-038 [CPL 2-1.38] (October 31, 2002). Also available as a 948 kb PDF, 51 pages. Provides information to assist compliance personnel in performing inspections in electric power generation, transmission, and installations, including that of distribution lines and other equipment.

b) OSHA Technical Manual (OTM), TED 01-00-015 [TED 1-0.15A] (January 20, 1999). Assists OSHA Compliance Safety and Health Officers (CSHOs) in hazard recognition and provides guidance in accident prevention. Serves as a source of advice for CSHOs on safety and health issues.

c) Inspection Guidelines for 29 CFR 1910, OSHA STD 01-06-006 [STD 1-6.6] (June 16, 1995). Provides inspection assistance related to personal protective equipment (PPE) (29CFR1910, Subpart I) to assist OSHA CSHOs performing inspections in general industry.

d) Electrical Safety-Related Work Practices—Inspection Procedures and Interpretation Guidelines. OSHA STD 01-16-007 [STD 1-16.7] (July 1, 1991). Establishes policies and provides interpretive guidelines for uniform enforcement of the standard for electrical safety-related work practices, 29CFR1910.331 through 29CFR1910.335.

[18] For countries other than the U.S. application of alternate, appropriate safety-related standards shall be used.

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5. Framework specification

5.1 Framework specification introduction

5.1.1 General

This clause serves the function of defining framework application, styles, performance, dimensional, and environmental specifications for satisfying IEEE Std 1505-2010. It is presented in two subsections: (a) first as a general definition describing common framework attributes and requirements for meeting the standard, and (b) a second, more detailed specification unique to the respective framework style or subset of the RFI system. Within each of those subsections there is a further definition between receiver and fixture elements. The general and specific specifications combine to form the RFI framework definition of the standard that otherwise could not stand alone.

The framework is described in two supplier versions: (a) segmented and (b) continuous framework designs. Where under the segmented framework specification, the RFI framework may be fabricated or assembled in separate four connector slot frame elements with ribs/spacings (voided connector slot) at the mating frame points. Whereas under continuous framework, the framework design may be constructed as an integral unit of multiple conductor slots that permits voided connector slot (ribs/spacings) required for segmented integration to be used. Integrators/suppliers may combine both framework designs to support a specific test interface requirement. In each approach, the body contour, alignment points, hole patterns, surface areas, and actuator elements of either framework shall remain constant with each 76.2 mm (3.0 in) increment of the framework.

Another descriptive view of the framework is related to how multiple frames are integrated to create multiple tier horizontal or vertical implementation. Orientation is first addressed as either *end-to-end* and *side-by-side* integration. Neither approach changes any framework specification, other than illustrate how frames are iterated to create multi-tier system (see 5.8.3 for more information).

End-to-end design describes the placement of RFI frames in an orientation that aligns the connectors in an end-to-end, stacking multi-tier fashion in either a vertical or horizontal fashion (see 5.8.3 for more information). Side-by-side design places in adjacent fashion to align the connectors in a side-by-side manner (see 5.8.3 for more information). Either design can be placed in a *horizontal* or *vertical* implementation.

5.2 Framework general specification

5.2.1 Framework physical footprint options

Rule 5.2.1a: The physical footprint of a segmented framework shall be in accordance with 5.5.2 and 5.8.3.1. The physical footprint of a continuous framework is illustrated in Figure 2, and can be applied as shown in Figure 3.

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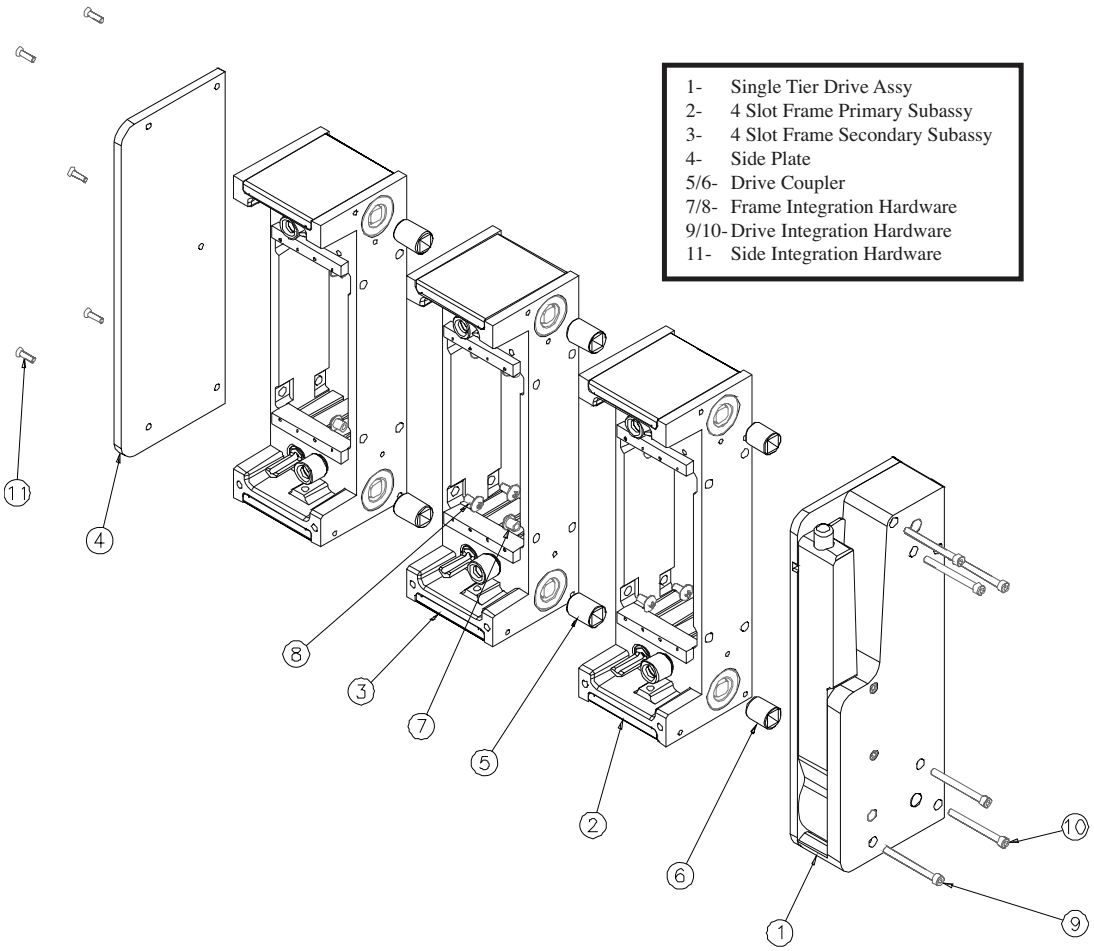


Figure 1—Receiver segmented framework layout design

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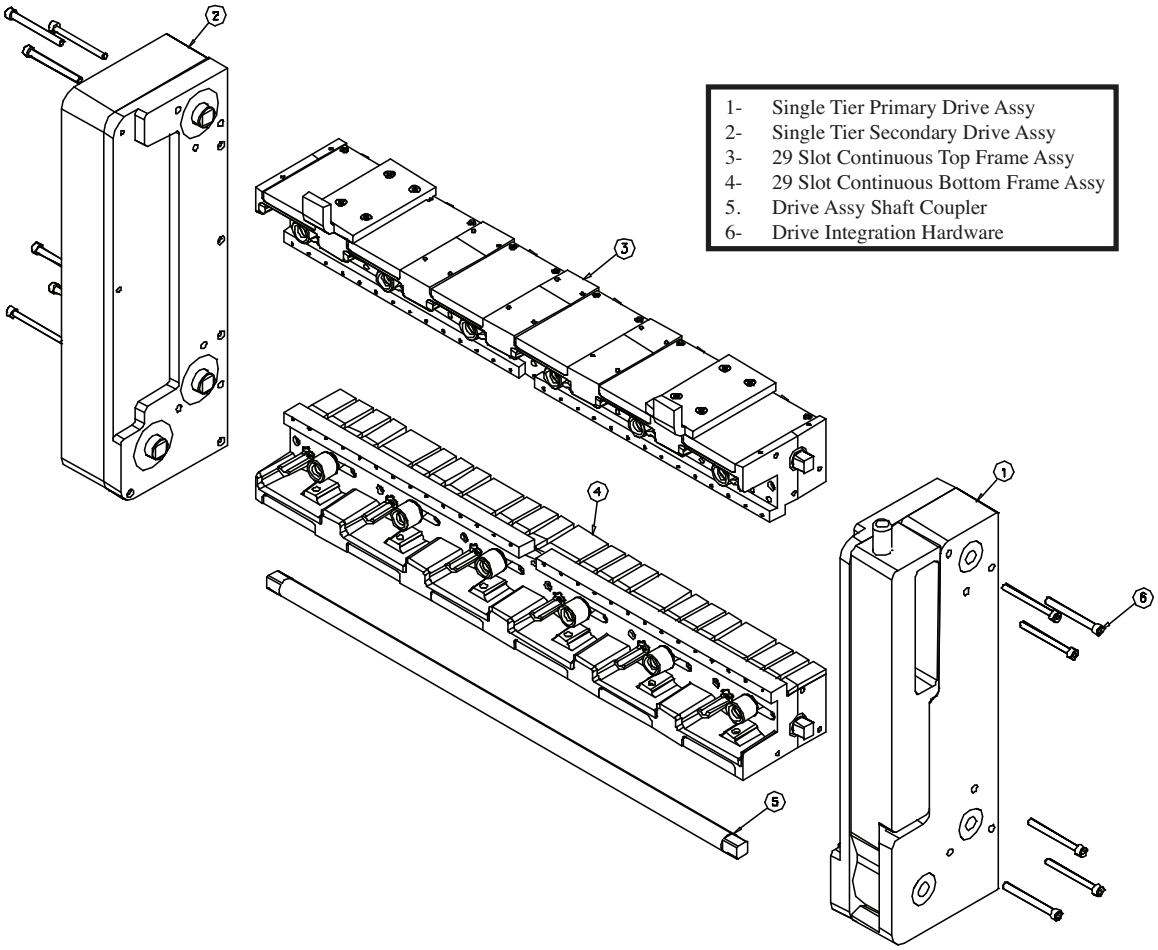


Figure 2—Receiver continuous framework layout design

Rule 5.2.1b: The framework assembly shall include alignment, keying, securing, and mechanical engagement devices and elements to permit user-friendly operation and to promote safety. Framework shall support the following:

a) Scalable integration of the fixture frames to the receiver frame in connector slot increments of 1, 4, 9, 14, 19, 24, and 29 slots based upon 76.2 mm (3.0 in) wide framework segmentation and 15.24 mm (0.6 in) connector slot widths

b) Reconfigurable integration of the multiple type/width connectors (1, 2, and 4 slot wide), at each slot or multiple slots

c) Fixture protective shroud intervals at framework/slot intervals 5, 10, 15, 20, and 25, where required

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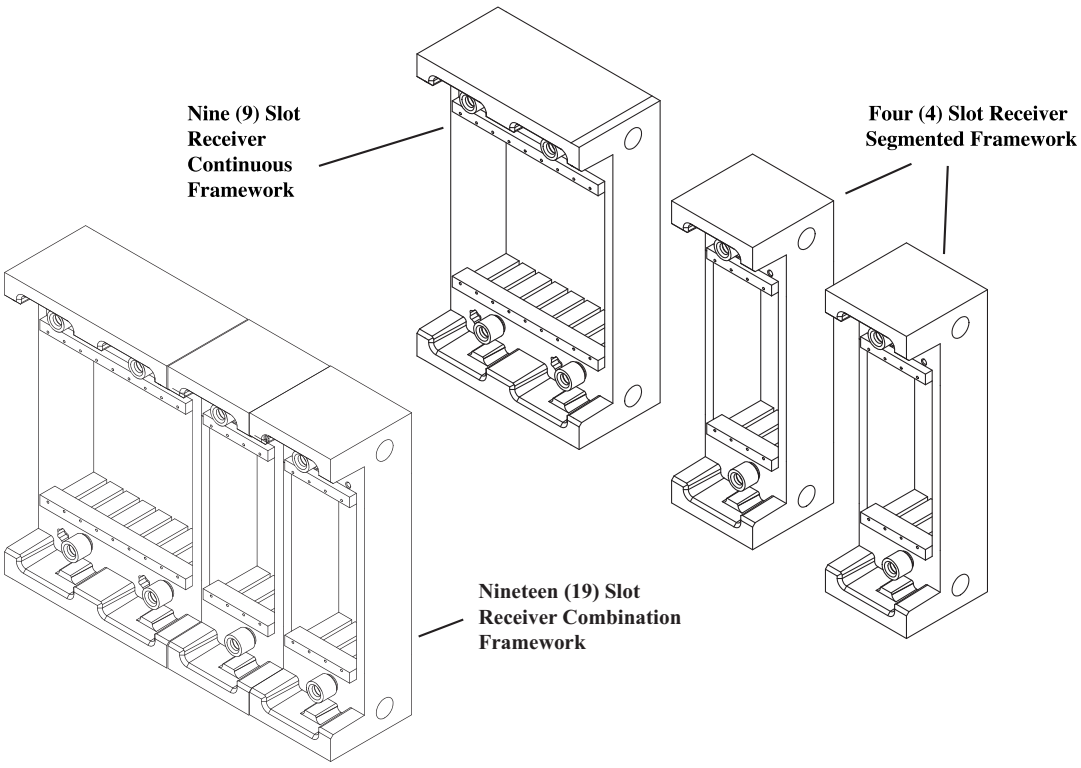


Figure 3—Receiver combination framework layout design

Rule 5.2.1c: The segmented framework specification (see Figure 1) shall use four connector module mounting slots and a 7.62 mm (0.30 in) shroud connector module keep-out space on each side. If incremented in four-slot sections under the segmented specification, a shroud spacing shall be provisioned at slot 5, 10, 15, 20, and 25 in the framework, to accommodate the protective shrouds of two adjoining fixtures.

Rule 5.2.1d: The continuous fixture and receiver framework specification (see Figure 2) is a side-by-side design implementation of multiple slot frames that expands connector side-by-side slots without applying blank spacing [representing combined adjoining fixture frames, 7.62 mm (0.30 in) fixture shroud connector keep-out space] for connector modules at slot 5, 10, 15, 20 and 25 in the framework in accordance with 5.8.3.1.

Permission: 5.2.1a: Integrators may apply a combination of segmented and continuous framework specifications (see Figure 3) or any combination of the connector module groups as determined by the specific application.

Rule 5.2.1e: The RFI framework shall be scalable in a side-by-side design from a minimum frame increment (four connector module slots) width of 76.2 mm (3.0 in), 279.4 mm (11.0 in) high, and 88.9 mm (3.5 in) deep, as illustrated in Figure 1, in 76.2 mm (3.0 in) frame increments per Clause 5. Integrators are permitted to increment side-by-side design fixed widths in 152.4 mm (6.0 in), 228.6 mm (9.0 in), 304.8 mm (12.0 in), 381 mm (15 in), up to a maximum 457.2 mm (18.0 in) [max supports 29 connector module slots including 7.62 mm (0.30 in) blank spacings as shown in Figure 2] to meet standard EIA equipment rack specifications.

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Rule 5.2.1f: The RFI framework shall be scalable in an end-to-end design from a minimum frame increment (four connector module slots) width of 76.2 mm (3.0 in), 279.4 mm (11.0 in) high, and 88.9 mm (3.5 in) deep, as illustrated in Figure 7, in 279.4 mm (11.0 in) high frame increments per Clause 5.

Permission 5.2.1b: Integrators are permitted to increment end-by-end design in either fixed heights of 279.4 mm (11.0 in) (see Figure 7), or arbitrary heights to meet system integration requirements.

Rule 5.2.1g: Integrators or users may add incremental receiver framework at anytime to satisfy any mix of fixture requirements, as shown in Figure 3.

5.3 Materials

Rule 5.3: Manufacturer shall identify materials used and the level of qualification met by the respective materials, as specified in 4.2. When a definite material is not specified, a material shall be used that enables the connectors and accessories to meet the form, fit, function, and performance requirement. Acceptance or approval of any constituent material by the buyer shall not be construed as a guaranty of the acceptance of the finished product from the manufacturer.

5.4 Restricted materials

Rule 5.4: Manufacturer shall limit the use of restricted materials and the level of qualification met by the respective materials, as specified in 4.2.4.

5.5 Dissimilar metals

Rule 5.5: Where dissimilar metals are used, they shall meet requirements as specified in 4.2.5.

5.6 Workmanship

Rule 5.6: Frameworks and accessories shall be uniform in quality and free from burrs, crazing, cracks, voids, pimples, chips, blisters, pinholes, sharp cutting edges, and other defects that adversely affect functionality or appearance of the product.

5.7 Design and construction

Rule 5.7: Frameworks shall be of the design, construction, and physical dimensions specified (see 5.8 for detailed product specifications). Compliance is a function of matching dimensional requirements of the standard where noted, and verification by the supplier or buyer that the product satisfies fit, form, and function interoperability in accordance with this standard's requirements (see 4.3).

5.7.1 Threaded parts

Rule 5.7.1: Unless otherwise specified, all threaded parts shall be in accordance with FED-STD-H28. Where practicable, all threads shall be in conformity with the coarse-thread series. The fine-thread series shall be used only for applications that might show a definite advantage through their use.

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5.7.1.1 Engagement of threaded parts

Rule 5.7.1.1: All threaded parts shall engage in accordance with ASME bolt criteria that establishes 1.5 to 2 times the diameter of the thread size, or a minimum of three full threads, unless otherwise specified in this document to be greater.

5.8 Framework assembly

5.8.1 Framework dimensional compliance

Rule 5.8.1a: The framework shall be designed to fully comply with the dimensional specifications described in 5.8.3 for proper electrical/mechanical operation under alignment (see 5.11), interchangeability (see 5.16), and durability requirements, in accordance with 5.21.

Rule 5.8.1b: The framework shall be designed to refine the engagement requirements with minimum dependence on mechanical float, through a telescopic alignment process (described and illustrated in Figure 4, Figure 5, and Figure 6), so that no misalignment or excessive force (see 5.18) is transmitted to the mating contact during engagement evolutions, per RFI qualification requirements (see 4.6.2).

Rule 5.8.1c: Critical interoperability areas, as illustrated in Figure 4, Figure 5, and Figure 6, represent key interface points that shall be met in accordance with this document's requirements (see 4.6.2.2) for interoperability between vendor products. These interoperability points shall serve as alignment between the mating surfaces of the receiver and fixture assemblies as previously discussed in 2.1.2. Detail descriptions are shown in subsequent Figure 4, Figure 5, and Figure 6.

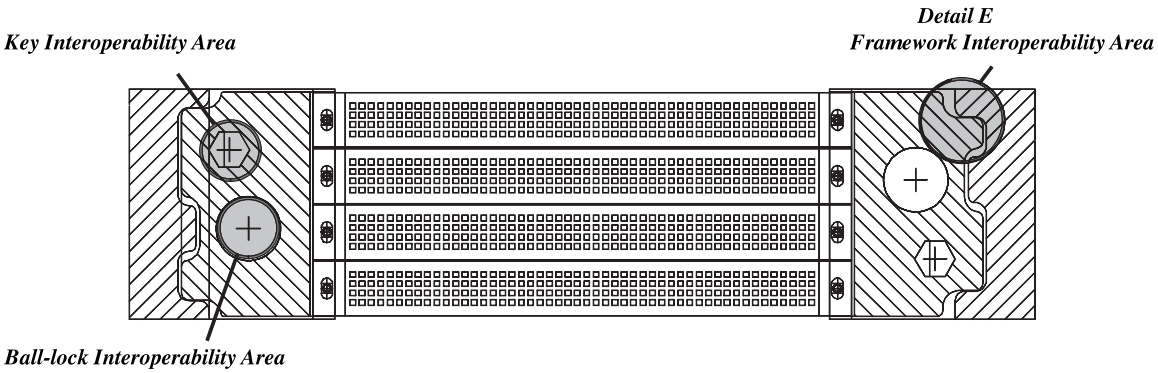


Figure 4—Segmented receiver/fixture top view, critical interoperability areas

Rule 5.8.1d: Dimensional tolerance shall be, unless otherwise stated, understood to be the following:

a) ±0.02 mm (± 0.10 in/± 0.1°), when linear/angular dimensional measurements in inches are to one decimal place

b) ±0.013 mm (± 0.050 in/± 0.05°), when linear/angular dimensional measurements in inches are to two decimal places

c) ±0.0013 mm (± 0.005 in/± 0.005°), when linear/angular measurements are to three decimal places

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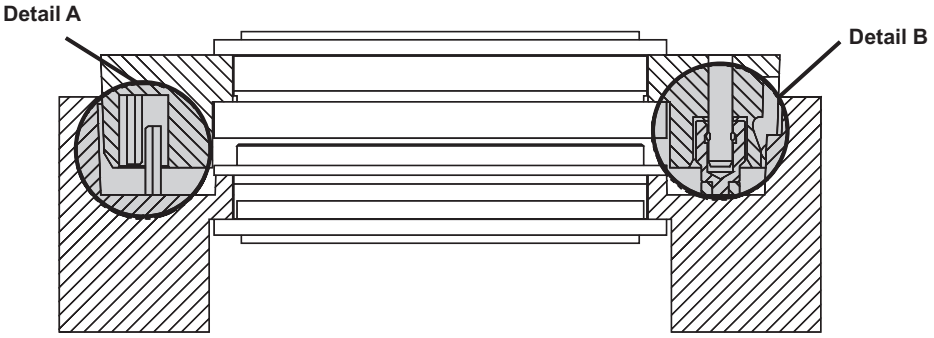


Figure 5—Receiver/fixture side view, signal modules disengaged, framework-critical interoperability areas

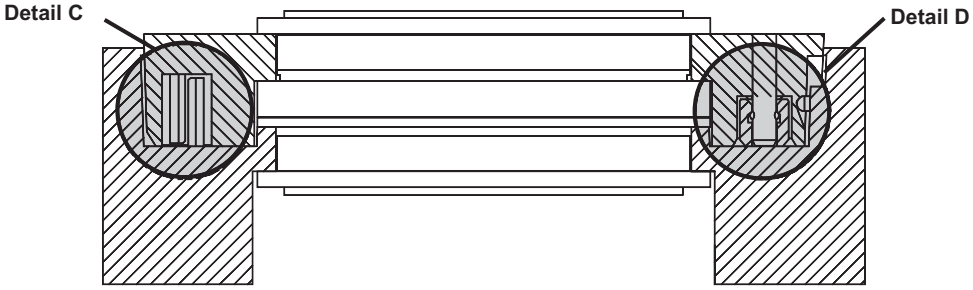


Figure 6—Receiver/fixture side view, signal modules engaged, framework-critical interoperability areas

5.8.2 Framework durability compliance

Rule 5.8.2: The framework shall be designed for proper operation without dependence on adjustment so that a minimum force is transmitted to the handle during mating and unmating under specified loads and environment conditions through a duration cycle test of 25 000 revolutions, without display of looseness, stroke/alignment dimensional change, or permanent displacement from its original, normal, fitted position at completion of the specified tests. Manufacturers shall validate conformance to this document per RFI qualification requirements in 4.6.2.4, Clause 5, and MIL-STD-1344A, Method 2002.1.

5.8.3 Body design

Rule 5.8.3a: Framework bodies shall be designed and constructed with proper sections and radii to prevent cracking, chipping, or breaking in assembly or in normal service. The framework shall be constructed in a side-by-side iteration, a placement of a four-slot frame next to another, or an end-to-end iteration, a placement of four slot frame on top of another, in accordance with Rule 5.8.3b and Rule 5.8.3c, to support scalable integration of the test interface as illustrated in Figure 7.

Permission 5.8.3: Framework bodies may be separated to accommodate instrument chassis alignment for direct coupling requirements, or building block and adjacent rack mounting schemes (see Figure 8). Implementation should attempt to define the space separating the framework, in accordance with increments established under the side-by-side and end-to-end iteration rules.

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Rule 5.8.3b: Side-by-side body integration, which places one four-slot frame in row next to one another or in multiple frames, shall be in accordance with this document *side-by-side segmented framework* design having ribs/spacings (voided connector slot), or *side-by-side continuous framework* without ribs, or combination of both. The body contour, alignment points, hole patterns, surface areas, and actuator elements of either framework remain constant. The side-by-side segmented framework and side-by-side continuous framework shall be dimensioned and iterated at 76.2 mm (3.0 in) intervals, as described in 5.8.3.1, 5.8.3.2, and 5.8.3.3, and utilize materials as specified in 5.3. As stated earlier, differences in the framework relate only to the presence of a connector at every 15.24 mm (0.60 in) spacing (slot) under side-by-side continuous framework, versus the side-by-side segmented framework specification that may or may not restrict use of a connector, at 76.2 mm (3.0 in) frame intervals, to provision for *receiver frame side supports,* and/or application of adjacent fixtures that have protective shroud sidewalls.

Rule 5.8.3c: End-to-end multi-tier body, which stacks frame on ends in either a horizontal and vertical integration, as illustrated in Figure 7, shall be in accordance with this document *end-to-end multi-tier framework* design having all of the side-by-side framework features related to body contour, alignment points, hole patterns, surface areas, actuator elements, and ribs/spacings (voided connector slot), where applicable. *multi-tier framework* shall be dimensioned and iterated at a minimum 245.75 mm (9.675 in) intervals, as described in 5.8.3.2, and utilize materials as specified in 5.3.

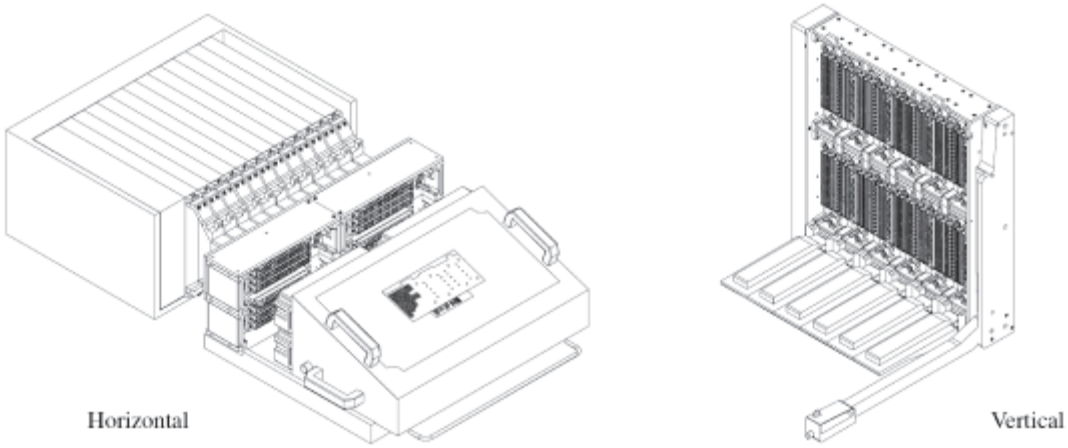


Figure 7—IEEE 1505 receiver, end-to-end multi-tier body horizontal and vertical integration based upon minimum increment 245.75 mm (9.675 in) spacing

5.8.3.1 Side-by-side receiver frame layout design

Rule 5.8.3.1: Receiver frame side-by-side layout design shall conform to the drawing specification illustrated in this document as either segmented framework (see Figure 8 and Figure 9); side-by-side continuous framework (see Figure 12 and Figure 13); side-by-side combination framework (see Figure 14 and Figure 15); side view framework, or combination of both, as also described in Figure 10 and Figure 11. Detailing contours and draft angles of the frame shall be adhered to in order to support alignment, as described in 5.8.1 casting/molding dimensional provisions.

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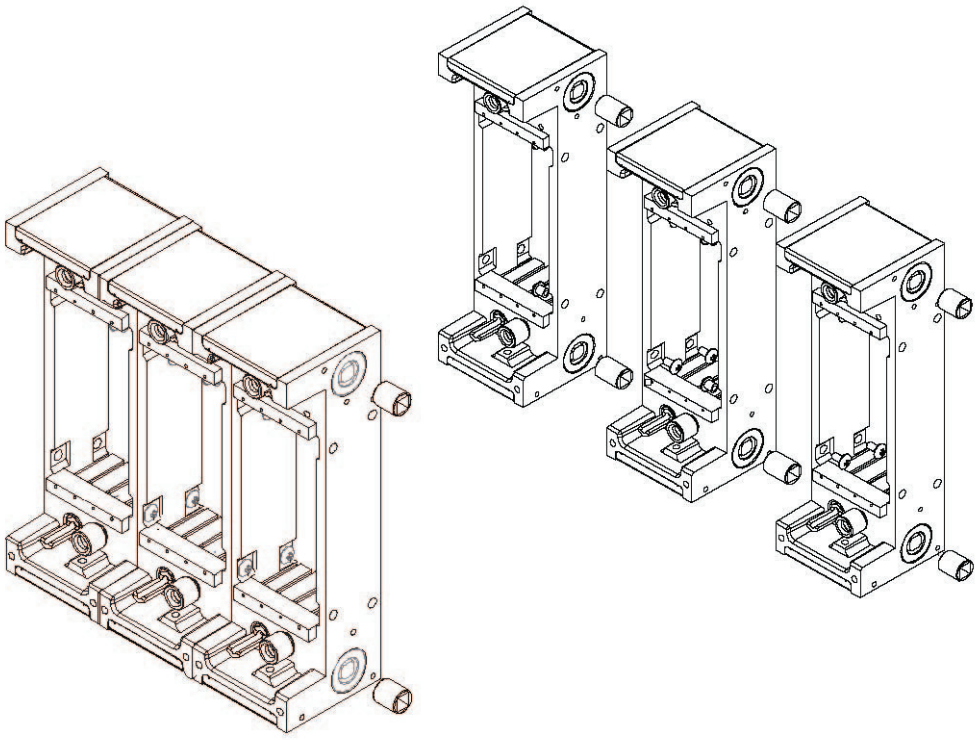


Figure 8—Segmented framework receiver layout design, perspective view, with connector mount spacing of 15.24 mm (0.60 in) and nonconnector slot for frame rib at 76.2 mm (3.0 in) spacings

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